Attorney's Docket No.: 12732-075002 / US5208/5209D1

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

plicant: Akira Ishikawa

Art Unit : 2826

Serial No.: 10/728,903

Examiner: Tuan N. Quach

Filed

: December 8, 2003

Title

: SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

## MAIL STOP RCE

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

Applicants note that, in addition to the three patents cited in the search report, the search report identifies related family patents. In the interest of efficiency, applicants have only submitted the three cited patents.

This statement is being filed with a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date:	0	26	05	

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Substitute	Form	PTO-1449
(Modified)		

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 12732-075002

Application No. 10/728,903

## **Information Disclosure Statement by Applicant** (Use several sheets if necessary)

Applicant Akira Ishikawa

December 8, 2003

Filing Date

Group Art Uni 2826

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. 1D	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,432,461	07/11/1995	Henley			06/28/1991
	AB	5,663,777	09/02/1997	Aoyama			12/27/1995
	AC	6,111,626	08/29/2000	Watanabe et al.			10/09/1998
	AD						
	AE						
	AF						
	AG					·	
	AH						
	AI						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Trans	slation
Initial	ID D	Number	Date	Patent Office	Class	Subclass	Yes	No
	AJ							
	AK					•		
	AL							
·	·AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner Initial	Desig. ID	Document		
	AO	Supplementary Search Report (Application No. 2001-05539-1; SG5208/5209D1) dated September 30, 2004.		
	AP			
	AQ			

Examiner Signature	Date Considered						
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							